

S arch Notes

Application/Control No.

10/629,152

Examiner

John J. Park

Applicant(s)/Patent under
Reexamination

WU ET AL.

Art Unit

2876

SEARCHED

Class	Subclass	Date	Examiner
235	492		
235	383		
235	380		
235	439		
235	435		
343	895		
713	200		
709	225	1/19/2005	JP

INTERFERENCE SEARCHED

Class	Subclass	Date	Examiner

**SEARCH NOTES
(INCLUDING SEARCH STRATEGY)**

	DATE	EXMR
EAST		
Text Search		
Consulted with S. Paik in AU 2876	1/19/2005	JP